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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
JH	AA 2002/0054962	05/09/02	Huang			
JH	AB 2001/0055873	12/27/01	Watanabe et al.			
JH	AC 6,340,435	01/22/02	Bjorkman et al.			
JH	AD 6,043,145	3/28/00	Suzuki et al.			
JH	AE 5,889,330	03/30/99	Nishimura et al.			
JH	AF 5,763,954	6/09/98	Hyakutake			
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JH	AH 5,604,380	02/18/97	Nishimura et al.			

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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
JH	AI 11-40543	02/12/99	Japan			Abstract	
JH	AJ 2001-60584	3/6/01	Japan			X	
JH	AK WO 99/21217	4/29/99	PCT				
JH	AL WO 99/52135	10/14/99	PCT				
JH	AM WO 00/14786	3/16/00	PCT			X	
JH	AN EP 1 120 822	01/08/02	EP				
JH	AO 7-94483	4/7/95	Japan			Abstract	
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AS	C.Y. Chang et al., "ULSI Technology", Chapter 8, pages 418-421, McGraw Hill, 1996
AT	Shyam P. Murarka et al., "Copper-Fundamental Mechanisms for Microelectronic Applications", Chapter 6, pages 175-201, John Wiley & Sons, 2000

Examiner Lynne A. Farley Date Considered 4/28/05